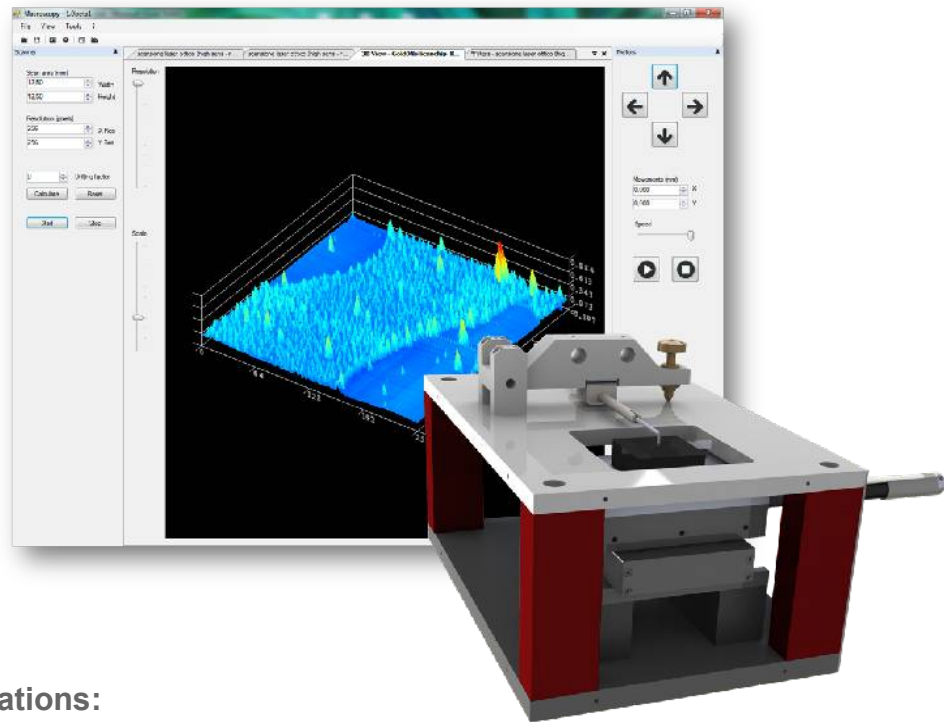


Stylus Profilometer



Applications:

- Step height measurements
- Surface roughness measurements
- Quantify scratch and dig features, wear depth, width and volume
- Surface flatness or curvature measurements
- 2D thin film measurements
- Surface profiling
- Dimensional analysis and surface texture

The rapid evolution in the fields of nanotechnology, thin film, data storage, MEMS, opto-electronics and other new material has lead to the need of more precise surface characterization for process development and manufacturing control of scientific research.

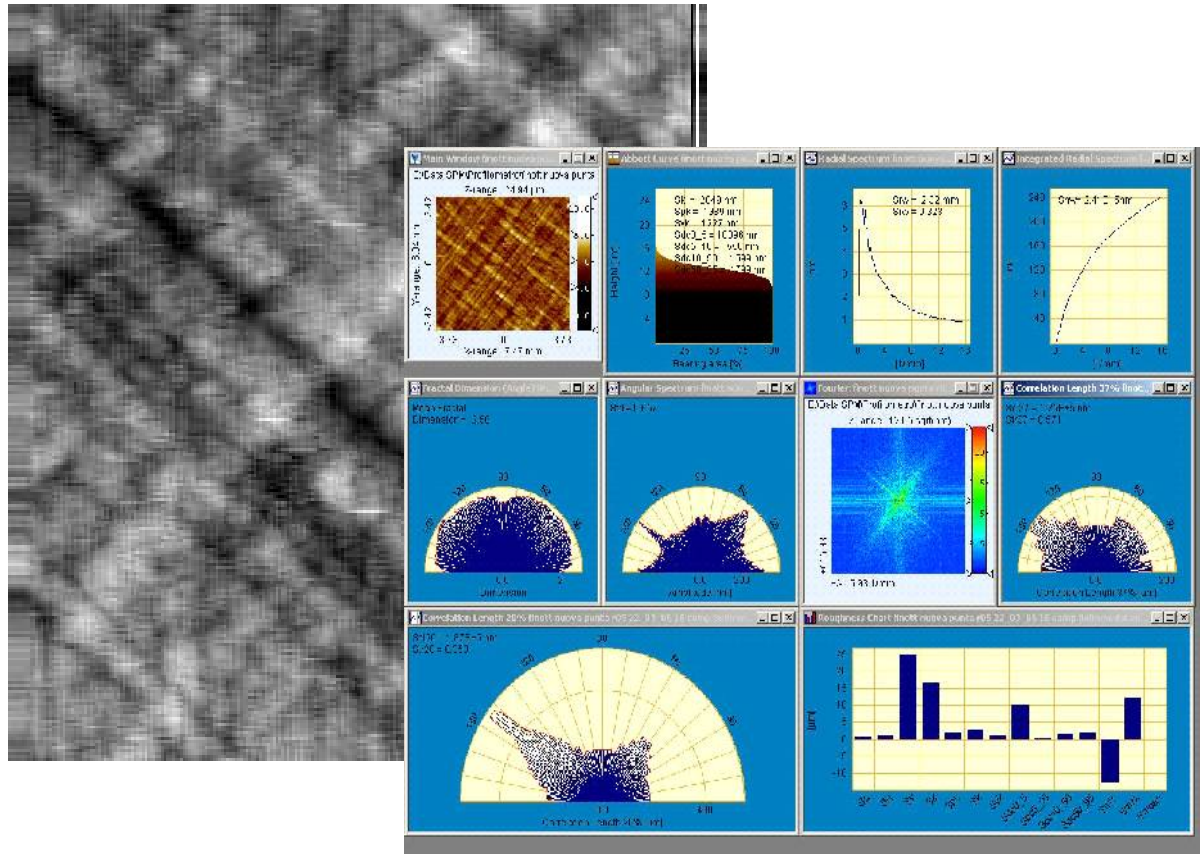
In order to meet a wide range of application and budgetary requirements, the APE Stylus Profilometer accurately characterizes film thickness, roughness and defects on samples up to 25 mm.

The high-precision stage moves a sample according to a user-programmed scan length, speed and stylus force. The video monitor allows a view of both the physical scanning of the sample and the plotting of the data simultaneously.

The graphical user interface has a multi-window interface that allows a user to continually acquire and display scan data. The software comes equipped with filters for immediate analysis of acquired data. This permits the user to quickly analyse the data in a fully flexible environment.

Key features:

- Contact surface profiling by stage scanning
- Generates 1D, 2D and 3D profiles
- Z range up to 1mm
- XY scanning range up to 25 mm x 25mm
- Simple operation with user friendly software interface
- Integrated color optical camera for direct sample viewing during scanning



Profile analysis on a wood sample

Measuring method	Skid measurement
Measuring range Z-axis	Up to 1 mm
Measuring range X Y -axis	25 mm
Profiles	1D; 2D; 3D
Evaluation parameter	Ra, Rz, Rq, R3z, Rt, Rp, Rv, Lo, Δa , Δq ,
Sampling length (L)	25 mm
Arbitrary length	0,1 – 25 mm

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